

HP 37717C communications performance analyzer

Configuration guide

Effective from February 1998





Small Siemens cross-reference

All options listed in the following pages are BNC. If you need small Siemens connectors, use the table below to select equivalent Siemens option.

BNC		Small Siemens
UKK UKJ 110 UKN UKZ	\rightarrow \rightarrow	USB USA not applicable USE not applicable
120 A3R A1T	\rightarrow \rightarrow	not applicable A3S A1U 141
140 A3K UHN	\rightarrow	141 A3Q US9
A3L A3V A3N	\rightarrow \rightarrow \rightarrow	A3M A3W A3P
0YK USL		not applicable not applicable
UH3 200	→	US7 not applicable
UH1 USN UKT 130 131		not applicable not applicable not applicable not applicable not applicable
0YH		not applicable
UHC A3D A3B	→	US6 not applicable not applicable
UKX		not applicable
UH4 UH5 UH6 UH7 UH8 UKP UKQ		not applicable not applicable not applicable not applicable not applicable not applicable not applicable

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Introduction

Your choice of test capability

The HP 37717C communications performance analyzer supports comprehensive functional test and jitter capability to help you test your PDH/DSn, SONET/SDH and ATM networks or network equipment. The analyzer comprises a mainframe with large color display and integral floppy disk drive, optional 80-column graphics printer, and includes power cord and operating manuals. You add the test capability you require by selecting from the optional test modules.

To meet your specific test needs, just order the capability you require. Simply order the HP 37717C analyzer and choose the application orientated options you require, from the tables in the pages that follow. Remember, you can configure your analyzer to simultaneously include PDH/DSn, SONET/SDH, ATM and jitter, or you can configure it to contain PDH/DSn only, SDH only, SONET/SDH only, ATM only or almost any combination.



HP 37717C communications performance analyzer with color display, floppy disk drive as standard and optional integrated printer.

All the power you need for comprehensive performance testing.

Select optional PDH/DSn, SONET/SDH, ATM cell layer, ATM services and jitter modules from an expanding range of options:

- ATM services layer testing with/without native LAN connectivity
- ATM cell layer generation and measurement
- SONET/SDH electrical interfaces
- SONET/SDH optical interfaces (1310 and 1550 nm)
- SONET/SDH binary interfaces
- PDH and SDH jitter/wander Tx and Rx
- DSn testing (DS1, DS3, E1, E3 structured)
- Multiple PDH outputs
- PDH testing (704 kb/s to 140 Mb/s)
- PDH binary interfaces with external clock input
- Printer/remote interfaces
- Graphics printer.

1. STM-4o/STM-1o plus jitter

Example user requirements

- PDH (2, 8, 34, 140 Mb/s) mux/demux capability
- STM-1e (155 Mb/s) electrical interfaces
- STM-4o/STM-1o (1310 nm) optical interfaces
- Optical power measurement
- Jitter and wander generation
- Jitter measurement (at all above interface rates)
- Graphics printer
- FC/PC optical adapters.

	Option code	Slots used
1. PDH/DSn and ATM test and interfaces option	UKJ	2
2. SONET/SDH test and interfaces option	A3R	2
3. Wander and jitter generation option	A3K	1
4. Wander and jitter measurement option	A3N	2
5. ATM services layer test option		
6. PDH binary interfaces option		
7. Optical interfaces option	131	Reserved
8. SONET/SDH binary interfaces option		
9. Multiple PDH interfaces option		
10. Remote-control/external-printer interfaces option		Reserved
11. Printer option	UKX	_
12. Optical adaptor option	UH4	—

2. ATM services and jitter

Example user requirements

- STM-1/OC-3c optical interfaces (1310 nm)
- DS1, DS3, E1, E3, STM-1e electrical interfaces
- ATM cell layer testing
- ATM Channel View, rate history, graphical CDV
- Jitter and wander generation (E1, E3, STM-1)
- Jitter measurement (E1, E3, STM-1)
- Screen dumps to printer
- LAN remote control
- FC/PC optical adapters.

		code	used
1.	PDH/DSn and ATM test and interfaces option	UKZ	2
2.	SONET/SDH test and interfaces option	A1T	2
3.	Wander and jitter generation option	A3K	1
4.	Wander and jitter measurement option	A3V	2
5.	ATM services layer test option	0YK	1
6.	PDH binary interfaces option		
7.	Optical interfaces option	UH1	Reserved
8.	SONET/SDH binary interfaces option		
9.	Multiple PDH interfaces option		
10.	Remote-control/external-printer interfaces option	A3B	Reserved
11.	Printer option	UKX	_
12.	Optical adaptor option	UH4	_

Ontion Slots

3. OC-12c, DS3 structured, HP-IB

Example user requirements

- PDH (DS1, DS3, E1, E3) mux/demux capability
- STS-1/STS-3 (52/155 Mb/s) electrical interfaces
- OC-12c (for clear channel testing)
- OC-12c/OC-3/OC-1 (1310 nm) optical interfaces
- Optical power measurement.
- RS-232-C/HP-IB remote control
- Remote PC operation (needs HP E4540A distributed network analyzer software).
- FC/PC optical adapters.

		Option code	Slots used
1.	PDH/DSn and ATM test and interfaces option	110	2
2.	SONET/SDH test and interfaces option	120	2
3.	Wander and jitter generation option		
4.	Wander and jitter measurement option		
5.	ATM services layer test option		
6.	PDH binary interfaces option		
7.	Optical interfaces option	131	Reserved
8.	SDH binary interfaces option		
9.	Multiple PDH interfaces option		
	Remote-control/external-printer interfaces option	A3D	Reserved
11.	Printer option		_
12.	Optical adaptor option	UH4	_
	Distributed network analyzer firmware	USS	_

Configuring the HP 37717C communications performance analyzer

There are reserved slots for optical interfacing and remote-control modules. In addition, you have a maximum of **eight** user-configurable slots to add PDH/DSn, SONET/SDH, ATM and jitter capability. Ensure that the number of slots used does not exceed **eight**.



Step 1 Review sections 1 to 12 in the following pages to determine the capability you require. In each section, select one option as required and tick the option box.

Step 2 Enter the option code and slots used in the table below. Confirm slots used does not exceed eight slots.

		Option code	No. of slots	Slots used
1.	PDH/DSn and ATM test and interfaces option		2	
2.	SONET/SDH test and interfaces option		2	
3.	Wander and jitter generation option		1	
4.	Wander and jitter measurement option		1 or 2	
5.	ATM services layer test option		1 or 2	
6.	PDH binary interfaces option		1	
7.	Optical interfaces option		_	Reserved
8.	SONET/SDH binary interfaces option		1	
9.	Multiple PDH interfaces option		1	
10.	Remote-control/external-printer interfaces option		_	Reserved
11.	Printer option		—	—
12.	Optical adaptor options			—
	Total numbe	er of slots	used	

Step 3 Check that you have specified both test and interfacing for all required capabilities.

Your local HP sales representative will be happy to help you configure the HP 37717C analyzer to match your specific needs.

Module interworking section

The following three tables indicate which modules are capable of networking with each other. Choose one from each category (if required) \dagger

PDH/SDH and ATM cell layer supported configurations

PDH/ATM cell test	STM-0e/STM-1e test	Optical	Jitter, wander and slips
and PDH interfaces	and interfaces	interfaces	testing – generation
Option UKKPage 8Unstructured PDH: 0.7, 2, 8,34 and 140 Mb/s.Option UKJPage 8Structured PDH: 2, 8, 34 and140 Mb/s.Option UKNPage 8ATM cell: 2, 34 and 140 Mb/s(includes all capability of option UKJ).Option UH3†Page 9Binary (NRZ) clock and data plus external clock input. Must also order option UKK, UKJ or UKN.Option UHC†Page 11Three additional 2, 8, 34 and 140 Mb/s outputs. Must also order option UKK, UKJ or UKN.	Option A3R Page 8 STM-0e (52 Mb/s) and STM-1e (155 Mb/s) electrical interface: STM-0/STM-1 overhead access, thru mode and pointer sequences , TU-12, TU-2, VC-3 and VC-4 mappings.	Option UH1Page 10155 Mb/s (1310 nm).Option 130Page 10622/155/52 Mb/s (1310 and1550 nm), optical powermeasurement.Option 131Page 10622/155/52 Mb/s (1310 nm),optical power measurement.Option 0YH†Page 10622/155/52 Mb/s binary (NRZ)interfaces. Must also orderoption 130 or 131.	Option A3KPage 9PDH and SDH jitter and wander generation.Page 9PDH and SDH jitter generation.Page 9PDH and SDH jitter generation.Jitter, wander and slips testing - measurementOption UHNPage 9PDH jitter measurement: 2, 8, 34 and 140 Mb/s.Page 9Option A3LPage 9STM-1e line and PDH jitter measurement: 2, 8, 34, 140 and 155 Mb/s.Page 9STM-10, STM-1e line and PDH jitter measurement: 2, 8, 34, 140 Mb/s and 155 Mb/s.Option A3V Page 9STM-40, STM-10, STM-1e line and PDH jitter measurement: 2, 8, 34, 140 Mb/s, 155 Mb/s.Option A3N Page 9STM-40, STM-10, STM-1e line and PDH jitter measurement: 2, 8, 34, 140 Mb/s, 155 Mb/s and 622 Mb/s.Page 9

Dual standard SONET/SDH and DSn/PDH supported configurations

Option 110Page 8 Structured PDH: DS1, DS3, E1, E3.Option 120Page 8 STS-1/STM-0e (52 Mb/s) and STS-3/STM-1e (155 Mb/s) electrical interface: Overhead access, thru mode and pointer sequences. VT1.5/TU-11, VT2/TU-12, VT6/TU-2, VC-3/STS-1 SPE and VC-4/STS-3c SPE mappings.Option 130Page 10 (155 Mb/s (1310 nm).Option 140Page 9 PDH, 155 Mb/s, 622 Mb/s jitter and wander generation.Option UKJPage 8 Structured PDH: 2, 8, 34 and 140 Mb/s.VT1.5/TU-11, VT2/TU-12, VT6/TU-2, VC-3/STS-1 SPE and VC-4/STS-3c SPE mappings.Option 131Page 10 (622/155/52 Mb/s optical interface (1310 nm), optical power measurement.Option UHN Page 9 PDH, 155 Mb/s, 622 Mb/s (1310 and 1550 nm), optical power measurement.Option UKNPage 9 Binary (NRZ) clock and data plus external clock input.Page 9 Binary (NRZ) clock and data plus external clock input.Page 9 PDHDetion A3L Page 9 PDH jitter measurement.Option UKJOption Offion UKKPage 9 PDH jitter measurement.Option A3L Page 9 PDH jitter measurement.Option UKJ).Option A3L Page 9 PDH jitter measurement.Page 9 PDH jitter measurement.Option A3L Page 9 PDH jitter measurement.Page 9 PDH jitter measurement.Option A3S Option 130 or 131.Page 9 PDH jitter measurement.	PDH/DSn interfaces	SONET/SDH test and interfaces	Optical interfaces	Jitter, wander and slips testing – generation*
UKJ, UKN or 110. Option A3N Page 9 622 Mb/s and 155 Mb/s optical, electrical and PDH jitter measurement.	Structured PDH: DS1, DS3, E1, E3.Option UKKPage 8 Unstructured PDH: 0.7, 2, 8, 34 and 140 Mb/s.Option UKJPage 8 Structured PDH: 2, 8, 34 and 140 Mb/s.Option UKNPage 8 ATM cell: 2, 34 and 140 Mb/s (includes all capability of option UKJ).Option UH3†Page 9 Binary (NRZ) clock and data plus external clock input. Must also order option UKK,	Option 120 Page 8 STS-1/STM-0e (52 Mb/s) and STS-3/STM-1e (155 Mb/s) electrical interface: Overhead access, thru mode and pointer sequences. VT1.5/TU-11, VT2/TU-12, VT6/TU-2, VC-3/STS-1 SPE and VC-4/STS-3c SPE	Option UH1Page 10155 Mb/s (1310 nm).Option 130Page 10622/155/52 Mb/s opticalinterface (1310 and1550 nm), optical powermeasurement.Option 131Page 10622/155/52 Mb/s opticalinterface (1310 nm), opticalpower measurement.Option 09H†Page 10622/155/52 Mb/s binary(NRZ) interfaces. Must also	Option A3KPage 9PDH, 155 Mb/s, 622 Mb/sjitter and wander generation.Option 140Page 9As option A3K, but withoutwander generation.Jitter, wander and slipstesting - measurement*Option UHNPage 9PDH jitter measurement.Option A3LPage 9155 Mb/s electrical and PDHjitter measurement.Option A3VPage 9155 Mb/s optical, electricaland PDH jitter measurement.Option A3NPage 9622 Mb/s and 155 Mb/soptical, electrical and PDH

Broadband ATM services supported configurations

ATM cell test interfaces	STM-1e test and interfaces	Optical interfaces	Jitter, wander and slips testing – generation*
Option UKN¹ Page 8 ATM cell generation and analysis: 2, 34 and 140 Mb/s (includes all capability of option UKJ structured PDH). Option UKZ² Page 8 Generation and measurement of ATM payloads: 1.544 (DS1), 44.736 (DS3), 2.048 (E1) and 34.368 (E3) Mb/s. ¹ <i>ITU-T</i> ² <i>ANSI/ITU-T</i>	Option A1TPage 8STM-1e (155 Mb/s) electrical interface. Overhead access, thru mode and pointer sequences. TU-12, TU-2, VC-3 and VC-4 mappings.(Provides STM-10 output when option UKN and optical interface option are selected. STM-10 and OC-3c are provided when option UKZ and an optical interface option are selected).	Option UH1Page 10155 Mb/s (1310 nm).Option USNPage 10622/155 Mb/s (1310 and1550 nm), optical powermeasurement.Option UKTPage 10622/155 Mb/s (1310 nm),optical power measurement.	Option A3KPage 9PDH, 155 Mb/s, 622 Mb/sjitter and wander generation.Option 140Page 9As option A3K but withoutwander generation.Jitter, wander and slipstesting - measurement*Option UHNPage 9PDH jitter measurement.
ATM services layer test			Option A3LPage 9155 Mb/s electrical and PDHjitter measurement.Option A3VPage 9155 Mb/s optical, electrical
Option 0YK Page 9 Adds Channel View, graphical display of CDV, AAL analysis, rate history, benchmark traffic generation. Must also order option UKN or UKZ,			and PDH jitter measurement. Option A3N Page 9 622 Mb/s, 155 Mb/s optical, electrical and PDH jitter.
Option USL Page 9 Adds Ethernet LAN connectivity testing plus all features of option 0YK. Must also order option UKN or UKZ.			

† Where specified two modules may be ordered from certain categories (ie. UH3, UHC, 0YH).

* NB Jitter generation and measurement does not include DS1, DS3 and 52 Mb/s. PDH jitter depends on options fitted. If option UKK/UKJ/UKN fitted then PDH jitter generation and measurement is provided at E1/E2/E3/E4. If option 110 fitted then PDH jitter generation and measurement capability is provided at E1 and E3. 622 Mb/s and 155 Mb/s jitter presented in ITU-T terminology as is specified in the HP 37717B/C communications performance analyzer technical specifications (publication number 5966-0892E).

For compliance to Bellcore standards, please contact you local Hewlett-Packard representative for details.

Please contact your local sales office if you require module interworking capability not specified here.

All modules work with UKX (printer), A3B/A3D (remote control) and USS (distributed network analyzer software).

	Option code	No of slots	Tick one
1. PDH/DSn and ATM test and interfaces options			
Choose one option (if required). All options provide PDH interfaces and PDH test capability.			
• Unstructured PDH testing: 0.7, 2, 8, 34 and 140 Mb/s interfaces plus an error output	UKK	2	
\bullet Structured PDH testing: 2, 8, 34 and 140 Mb/s interfaces (64 kb/s and n $\times64$ kb/s testing)	UKJ	2	
• ATM cell generation and analysis: 2, 34 and 140 Mb/s interfaces† – includes all capability of option UKJ (structured PDH testing).	UKN	2	
• Structured DSn/PDH testing: DS1, DS3, E1 and E3 interfaces	110	2	
• ATM cell generation and analysis: DS1, DS3, E1 and E3 interfaces	UKZ*	2	
 † If you need ATM cell generation and analysis at STM-1, then also order STM-0e/STM-1e option A3R (section 2). ‡ If you need OC-3c, then also order STM-1e option A1T (section 2) and appropriate optical interfaces and adaptor options (sections 7 and 12). * Option UKZ does not support option A3R or 120 at present. Please refer to module interworking section (pages 6 and 7). 			
	Option code	No of slots	Tick one
2. SONET/SDH test and interfaces options			
Choose one option (if required). These options provide SDH electrical interfacing and SDH test capability.			
• SDH test module: STM-0e (52 Mb/s) and STM-1e (155 Mb/s) electrical interfaces, STM-0/STM-1 overhead access,thru mode and pointer sequence generation, TU-12, TU-2, VC-3 and VC-4 mappings plus frequency offset generation, alarm and error generation/detection plus an error output, SDH alarm and BIP scan, tributary scan and protection switch times.	A3R*	2	
• SONET/SDH test module: STS-1/STM-0e (52 Mb/s) and STS-3/STM-1e (155 Mb/s)electrical interfaces, overhead access,thru mode and pointer sequence generation, VT1.5/TU-11, VT2/TU-12, VT6/TU-2, STS-1/VC-3 SPE and STS-3c/VC-4 SPE mappings plus frequency offset generation, alarm and error generation/detection plus an error output, offset generation and BIP scan, tributary scan and protection switch plus frequency and BIP scan.	·	2	
* Option A3R does not support option UKZ at present. Please refer to module interworking section (pages 6 and 7).			
[†] Option 120 does not support option UKZ and UHC at present. Please refer to module interworking section (pages 6 and 7).			
STM-1e (155 Mb/s) electrical interface: As per option A3R but without STM-0e (52 Mb/s)capability, and without an error output.	A1T	2	
	Option code	No of slots	Tick one
3. Wander and jitter generation options			
Choose on option (if required). For PDH jitter generation, also order PDH/DSn option (section 1). For SDH jitter generation, also order SONET/SDH option (secti plus appropriate optical interfaces and adaptor options (sections 7 and 12).	on 2)		
• PDH jitter generation: 2, 8, 34 and 140 Mb/s up to 80 UI (2 Mb/s).	140†	1	
SDH jitter generation: STM-1 (155 Mb/s) and STM-4 (622 Mb/s) up to 200 UI (STM-4).			
• All the capability of option 140 plus wander generation: 2 Mb/s, STM-1 (155 Mb/s) and STM-4 (622 Mb/s) up to 14400 UI (STM-4).	A3K	1	
† 8 and 140 Mb/s jitter generation requires a PDH option with 8 and 140 Mb/s interface to be fitted			

	Option code	No of slots	Tick one
4. Wander and jitter measurement options			
Choose one option (if required). If you need PDH jitter measurement then also order PDH/DSn interface option (section 1).			
• PDH (tributary) jitter and wander measurement: 2, 8, 34, 140 Mb/s, with HP1, HP2 and LP filters to ITU-T 0.171 plus 2 Mb/s wander and estimated frame slip measurement.	UHN	1	
• STM-1e line jitter and PDH (tributary) jitter; rms, peak-to-peak, auto jitter transferand wander measurement: 155 Mb/s electrical interface with HP1, HP2, LP and 12 kHz HP filters to ITU-T O.171/G.825.	A3L	2	
• STM-1o/STM-1e, plus all the capability of option A3L.	A3V	2	
• STM-4o/STM-1o/STM-1e, plus all the capability of option A3L	A3N	2	

 $\dagger~8~and~140~Mb/s~jitter$ measurement requires a PDH option with 8 and 140 Mb/s interface to be fitted

	Option code	No of slots	Tick one
5. ATM services layer test options			
Choose one option (if required). As these modules use the interfacing provided by a PDH/DSn and ATM test option, <u>must</u> also order ATM option UKN or UKZ (section 1)			
• Provides ATM and AAL capabilities including Channel View, rate history, graphical CDV, benchmark traffic.	0YK †	1	
• As per option 0YK (but occupying two slots) plus native Ethernet LAN connectivity tests.	USL†	2	
† Option 0YK and USL do not support options A3R and 120 at present			

[†] Option 0YK and USL do not support options A3R and 120 at present. Please refer to module interworking section (pages 6 and 7).

C DDII kinomy interfaces entions	Option code	No of slots	Tick one
6. PDH binary interfaces options			
Choose one option (if required). <u>Must</u> also order a PDH and ATM test option (section (Option UH3 does not support options UKZ, 0YK or USL at present.)	on 1).		
• PDH NRZ interfaces: Adds binary Tx clock and data, binary Rx clock and data, plus external clock input.	UH3 †	1	
• PDH synthesized BER testing bundle : Includes UH3 (binary clock and data), UKK (unstructured BER module) and HP 8647A synthesizer.	200	3	

† Option UH3 does not support options UKZ, OYK and USL at present. Please refer to module interworking section (pages 6 and 7).

	Option		Tick
7. Optical interfaces options	code		one
Choose one option (if required). All optical interfaces receive at 1310 and 1550 nm.			
Provides optical interfaces. <u>Must</u> also order STM-0e/STM-1e option A3R (section 2), and appropriate optical adaptor options (section 12).			
STM-1 optical interfaces only (for testing STM-1 only)*			
● 155 Mb/s optical interface: 1310 nm, –9 dBm output	UH1	reserved optical slot	
STM-4/OC-12c test and optical interfaces			
Provides optical interfaces, plus optical power measurement and STM-4 test functionality, ie, for STM-4 overhead access. <u>Must</u> also order 52/155 Mb/s option A3R or 120 (section 2), and appropriate optical adaptor options (section 12).			
● 622/155/52 Mb/s optical interfaces: Dual wavelength at 1310 nm, -10 dBm	130†		
output plus 1550 nm, –1 dBm output; includes STM-4/OC-12c, overhead access, thru mode and optical power measurement.			
● 622/155/52 Mb/s optical interfaces: 1310 nm, −10 dBm output; includes STM-4c/OC-12c, overhead access, thru mode and optical power measurement.	131†		
† Option 130/131 does not support option UKZ at present. Please refer to module interworking section (pages 6 and 7).			
STM-4 test and optical interfaces			
Provides optical interfaces. <u>Must</u> also order STM-1e option A1T (section 2), and appropriate optical adaptor options (section 12).			
622/155 Mb/s optical interfaces: Dual wavelength at 1310 nm, 1550 nm	USN*		
–10 dBm output plus 1550 nm, –1 dBm output; includes overhead access, thru mode and optical power measurement.			
622/155 Mb/s optical interfaces: 1310 nm, –10 dBm output;	UKT*	V	
includes overhead access, thru mode and optical power measurement (easily upgradeable to dual wavelength).			
* Available with ATM options 0YK, USL, UKZ only. When option UKZ (and A1T) are present, these interfaces also provide OC-3c capability.			

	Option code	No of slots	Tick if required
8. SONET/SDH binary interfaces option			
Choose if required. <u>Must</u> also order STM-4 test and optical interfaces option 130 or 131 (section 7).			
• 622/155 Mb/s NRZ interfaces. 50 ohm ECL Tx data and Tx clock outputs, plus Rx data and Rx clock inputs.	ОҮН	1	

	Option code	No of slots	Tick if required
9. Multiple PDH interfaces option		51015	requireu
 Choose if required. <u>Must</u> also order a PDH and ATM test and interface option UKK, UKJ or UKN (section 1). Three additional 2, 8, 34 and 140 Mb/s outputs. 	UHC	1	
	Option code		Tick one
10. Remote-control/external-printer interfaces options			
 <i>Choose one option (if required).</i> RS-232-C and HP-IB remote-control/external-printer interfaces LAN remote control, RS-232-C and HP-IB remote-control/external-printer interfaces 		reserved remote slot	
11. Printer option	Option code		Tick if required
 Choose if required. Integrated, full-width, 80-column graphics printer (for printing of graphics, results and screen dumps). 	Option	Uses lid	Tick as
12. Optical adaptor options	code		required
 If specifying an SDH optical interface and/or wander and jitter measurements, choose the connector adaptor type(s) to suit your particular requirements: FC/PC DIN47526 ST Biconic 	UH5 UH6	Not applicable	
 NEC D4 SC HMS-10/HP 	UKP	¥	Tick if
13. DNA	code		required
 Choose if required. Must also order a remote-control/external printer interface (see section 10). Allows the instrument to be used with HP E4540A distributed network analyzersoftware* for Windows®. Software allows remote, interactive control for centralized testing. * For full details of centralized testing using the HP 37717C analyzer and other telecom testers from HP, please ask your local HP representative for brochure 5964-2240E (distributed network analyzer software). 	USS	Not applicable	

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Optical coupler

HP15744A: Optical coupler.*

*Order the appropriate option. For full details of the HP 15744A optical coupler, please ask your local HP representative for a brochure. The optical coupler and graphics printer (option UKX) cannot both be fitted at the same time.

HP 15722A: Telephone handset for options UKJ or UKN.

Fiber optic cable

HP E4545A: 3 m fiber optic cable (FC/PC connectors).

Carrying cases and rack mount kit

HP 15910B: Soft, vinyl carrying case. HP 15772B: Hard, robust transit case. HP 15770A: Rack mount kit.

HP 15777C upgrade kit

Enhance the capabilities of the HP 37717C analyzer at a later date. To order HP 15777C upgrade kit options, contact your local HP sales representative.

Graphics printer paper

Printer paper: Part number 9270-1360.

Warranty

3-year warranty as standard.

Manuals and calibration certificate

Option AVA: Calibration manual. **Option OB2:** One additional operating manual.

Option OBF: One additional remote operation manual. **Option UK6:** Calibration certificate.

Standards conformance

CE mark:* The HP 37717C communications performance analyzer has full CE mark compliance and meets the following standards:

• ESD/mains fast transients/radiated

susceptibility: meets EN50082-1 (1991).
Radiation emissions/conducted emissions: meets EN55011 (1991).

Product safety: The HP 37717C communications performance analyzer meets the following safety standards:

• IEC 348/EN61010.

* All products sold in EC and ETSI countries must have the CE mark.

For more information about Hewlett-Packard test & measurement products, applications, services, and for a current sales office listing, visit our web site, http://www.hp.com/go/tmdir. You can also contact one of the following centers and ask for a test and measurement sales representative.

United States:

Hewlett-Packard Company Test and Measurement Call Center P.O. Box 4026 Englewood, CO 80155-4026 1 800 452 4844

Canada:

Hewlett-Packard Canada Ltd. 5150 Spectrum Way Mississauga, Ontario L4W 5G1 (905) 206 4725

Europe:

Hewlett-Packard European Marketing Centre P. O. Box 999 1180 AZ Amstelveen The Netherlands (31 20) 547 9900

Japan:

Hewlett-Packard Japan Ltd. Measurement Assistance Center 9-1, Takakura-Cho, Hachioji-Shi Tokyo 192, Japan Tel: (81) 426 56-7832 Fax: (81) 426 56-7840

Latin America:

Hewlett-Packard Latin American Region Headquarters 5200 Blue Lagoon Drive 9th Floor Miami, Florida 33126 USA (305) 267 4245/4220 Fax: (305) 267-4288

Australia/New Zealand:

Hewlett-Packard Australia Ltd. 31-41 Joseph Street Blackburn, Victoria 3130 Australia Tel: 1 800 629 485 (Australia) Tel: (0800) 738 378 (New Zealand) Fax: (61 3) 9210 5489

Asia Pacific:

Hewlett-Packard Asia Pacific Ltd. 17-21/F Shell Tower, Times Square 1 Matheson Street, Causeway Bay Hong Kong Tel: (852) 2599 7777 Fax: (852) 2506 9285

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